



## **Programmable controllers**

### **Part 9: Single-drop digital communication interface for small sensors and actuators (SDCI)**

**STANDARDS**  
Australia



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Australian Standard<sup>®</sup>

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**Part 9: Single-drop digital  
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sensors and actuators (SDCI)**

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## PREFACE

This Standard was prepared by the Standards Australia Committee IT-006, Industrial Process Measurement, Control and Automation.

The objective of this Standard is to specify a single-drop digital communication interface technology for small sensors and actuators (SDCIs) (commonly known as IO-Link™), which extends the traditional digital input and digital output interfaces as defined in AS IEC 61131.2 towards a point-to-point communication link. This technology enables the transfer of parameters to Devices and the delivery of diagnostic information from the Devices to the automation system.

This Standard should be read in conjunction with the other parts of the AS IEC 61131 series.

This Standard is identical with, and has been reproduced from, IEC 61131-9, Ed 1.0 (2013), *Programmable controllers—Part 9: Single-drop digital communication interface for small sensors and actuators (SDCI)*.

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- (a) In the source text ‘this part of IEC 61131’ should read ‘this Australian Standard’.
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60947-5-2	Part 5-2: Control circuit devices and switching elements—Proximity switches	60947.5.2	Part 5.2: Control circuit devices and switching elements—Proximity switches
		AS/NZS IEC	
61000	Electromagnetic compatibility (EMC)	61000	Electromagnetic compatibility (EMC)
61000-4-2	Part 4-2: Testing and measurement techniques—Electrostatic discharge immunity test	61000.4.2	Part 4.2: Testing and measurement techniques—Electrostatic discharge immunity test
61000-4-3	Part 4-3: Testing and measurement techniques—Radiated radio-frequency electromagnetic field immunity test	61000.4.3	Part 4.3: Testing and measurement techniques—Radiated radio-frequency electromagnetic field immunity test
61000-4-4	Part 4-4: Testing and measurement techniques—Electrical fast transient/burst immunity test	61000.4.4	Part 4.4: Testing and measurement techniques—Electrical fast transient/burst immunity test
		AS/NZS	
61000-4-5	Part 4-5: Testing and measurement techniques—Surge immunity test	61000.4.5	Part 4.5: Testing and measurement techniques—Surge immunity test
		AS/NZS IEC	
61000-4-6	Part 4-6: Testing and measurement techniques—Immunity to conducted disturbances, induced by radio-frequency fields	61000.4.6	Part 4.6: Testing and measurement techniques—Immunity to conducted disturbances, induced by radio-frequency fields

*Reference to International Standard**Australian Standard*

IEC

AS/NZS

61000-6-2 Part 6-2: Generic standards—  
Immunity for industrial  
environment

61000-6-4 Part 6-4: Generic standards—  
Emission standard for industrial  
environments

61000.6.2 Part 6.2: General standards—  
Immunity for industrial environment

61000.6.4 Part 6.4: Generic standards—  
Emission standard for industrial  
environments

AS IEC

61131 Programmable controllers

61131-1 Part 1: General information

61131-2 Part 2: Equipment requirements and  
tests

61131 Programmable controllers

61131.1 Part 1: General information

61131.2 Part 2: Equipment requirements and  
tests

Only normative references that have been adopted as Australian or Australian/New Zealand Standards have been listed.

The terms ‘normative’ and ‘informative’ are used to define the application of the annex to which they apply. A normative annex is an integral part of a standard, whereas an informative annex is only for information and guidance.

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## INTRODUCTION

### 0.1 General

IEC 61131-9 is part of a series of standards on programmable controllers and the associated peripherals and should be read in conjunction with the other parts of the series.

Where a conflict exists between this and other IEC standards (except basic safety standards), the provisions of this standard should be considered to govern in the area of programmable controllers and their associated peripherals.

The increased use of micro-controllers embedded in low-cost sensors and actuators has provided opportunities for adding diagnosis and configuration data to support increasing application requirements.

The driving force for the SDCI (IO-Link™<sup>1</sup>) technology is the need of these low-cost sensors and actuators to exchange this diagnosis and configuration data with a controller (PC or PLC) using a low-cost, digital communication technology while maintaining backward compatibility with the current DI/DO signals.

In fieldbus concepts, the SDCI technology defines a generic interface for connecting sensors and actuators to a Master unit, which may be combined with gateway capabilities to become a fieldbus remote I/O node.

Any SDCI compliant Device can be attached to any available interface port of the Master. SDCI compliant Devices perform physical to digital conversion in the Device, and then communicate the result directly in a standard format using "coded switching" of the 24 V I/O signalling line, thus removing the need for different DI, DO, AI, AO modules and a variety of cables.

Physical topology is point-to-point from each Device to the Master using 3 wires over distances up to 20 m. The SDCI physical interface is backward compatible with the usual 24 V I/O signalling specified in IEC 61131-2. Transmission rates of 4,8 kbit/s, 38,4 kbit/s and 230,4 kbit/s are supported.

The Master of the SDCI interface detects, identifies and manages Devices plugged into its ports.

Tools allow the association of Devices with their corresponding electronic I/O Device Descriptions (IODD) and their subsequent configuration to match the application requirements.

The SDCI technology specifies three different levels of diagnostic capabilities: for immediate response by automated needs during the production phase, for medium term response by operator intervention, or for longer term commissioning and maintenance via extended diagnosis information.

The structure of this standard is described in 4.8.

Conformity with IEC 61131-9 cannot be claimed unless the requirements of Annex G are met.

Terms of general use are defined in IEC 61131-1 or in the IEC 60050 series. More specific terms are defined in each part.

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<sup>1</sup> IO-Link™ is a trade name of the "IO-Link Consortium". This information is given for the convenience of users of this international Standard and does not constitute an endorsement by IEC of the trade name holder or any of its products. Compliance to this standard does not require use of the registered logos for IO-Link™. Use of the registered logos for IO-Link™ requires permission of the "IO-Link Consortium".

## 0.2 Patent declaration

The International Electrotechnical Commission (IEC) draws attention to the fact that it is claimed that compliance with this document may involve the use of patents concerning the point-to-point serial communication interface for small sensors and actuators as follows, where the [xx] notation indicates the holder of the patent right:

DE 10030845B4 EP 1168271B1 US 6889282B2	[AB]	Fieldbus connecting system for actuators or sensors
EP 1203933 B1	[FE]	Sensor device for measuring at least one variable
DE 10 2004 035 831.1	[SI]	Operational status of a computer system is checked by comparison of actual parameters with reference values and modification to software if needed
DE 102 119 39 A1 US 2003/0200323 A1	[SK]	Coupling apparatus for the coupling of devices to a bus system

IEC takes no position concerning the evidence, validity and scope of these patent rights.

The holders of these patents rights have assured the IEC that they are willing to negotiate licences either free of charge or under reasonable and non-discriminatory terms and conditions with applicants throughout the world. In this respect, the statements of the holders of these patent rights are registered with IEC.

Information may be obtained from:

[AB]	ABB AG Heidelberg Germany
[FE]	Festo AG Esslingen Germany
[SI]	Siemens AG Otto-Hahn-Ring 6 81739 Munich Germany
[SK]	Sick AG Waldkirch Germany

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights other than those identified above. IEC shall not be held responsible for identifying any or all such patent rights.

ISO ([www.iso.org/patents](http://www.iso.org/patents)) and IEC (<http://patents.iec.ch>) maintain on-line data bases of patents relevant to their standards. Users are encouraged to consult the databases for the most up to date information concerning patents.

## AUSTRALIAN STANDARD

**Programmable controllers**

## Part 9:

**Single-drop digital communication interface for small sensors and actuators (SDCI)****1 Scope**

This part of IEC 61131 specifies a single-drop digital communication interface technology for small sensors and actuators SDCI (commonly known as IO-Link™<sup>2</sup>), which extends the traditional digital input and digital output interfaces as defined in IEC 61131-2 towards a point-to-point communication link. This technology enables the transfer of parameters to Devices and the delivery of diagnostic information from the Devices to the automation system.

This technology is mainly intended for use with simple sensors and actuators in factory automation, which include small and cost-effective microcontrollers.

This part specifies the SDCI communication services and protocol (physical layer, data link layer and application layer in accordance with the ISO/OSI reference model) for both SDCI Masters and Devices.

This part also includes EMC test requirements.

This part does not cover communication interfaces or systems incorporating multiple point or multiple drop linkages, or integration of SDCI into higher level systems such as fieldbuses.

**2 Normative references**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60947-5-2, *Low-voltage switchgear and controlgear – Part 5-2: Control circuit devices and switching elements – Proximity switches*

IEC 61000-4-2, *Electromagnetic compatibility (EMC) – Part 4-2: Testing and measurement techniques – Electrostatic discharge immunity test*

IEC 61000-4-3, *Electromagnetic compatibility (EMC) – Part 4-3: Testing and measurement techniques – Radiated, radio-frequency, electromagnetic field immunity test*

IEC 61000-4-4, *Electromagnetic compatibility (EMC) – Part 4-4: Testing and measurement techniques – Electrical fast transient/burst immunity test*

IEC 61000-4-5, *Electromagnetic compatibility (EMC) – Part 4-5: Testing and measurement techniques – Surge immunity test*

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<sup>2</sup> IO-Link™ is a trade name of the "IO-Link Consortium". This information is given for the convenience of users of this international Standard and does not constitute an endorsement by IEC of the trade name holder or any of its products. Compliance to this standard does not require use of the registered logos for IO-Link™. Use of the registered logos for IO-Link™ requires permission of the "IO-Link Consortium".